

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/992,607 D 1721588	ADLER, GLENN JAY	
		Examiner	Art Unit	
		HENRY N. TRAN	2674	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,462,941	10-2002	Hulick et al.	361/683
B	US-5,796,382	08-1998	Beeteson, John S.	345/102
C	US-5,696,529	12-1997	Evanicky et al.	345/659
D	US-2001/0043188	11-2001	NAKAMURA, ATSUNORI	345/102
E	US-6,417,833	07-2002	Takemoto, Takahiro	345/102
F	US-6,426,736	07-2002	Ishihara, Junji	345/102
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
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T					

**NON-PATENT DOCUMENTS**

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U		
V		
W		
X		

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No. <del>08/092,601</del> 161721588	Applicant(s)/Patent Under Reexamination ADLER, GLENN JAY	
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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,301,106	10-2001	Helot et al.	361/686
B	US-6,625,015	09-2003	Yin, Memphis Zhihong	361/686
C	US-5,854,817	12-1998	Lee et al.	345/102
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
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S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages		
U			
V			
W			
X			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/721,588	ADLER, GLENN JAY	
		Examiner	Art Unit	Page 1 of 1
		Henry N. Tran	2629	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,462,941	10-2002	Hulick et al.	361/683
*	B	US-5,657,459	08-1997	Yanagisawa et al.	361/681
*	C	US-6,301,106	10-2001	Helot et al.	361/686
*	D	US-6,625,015	09-2003	Yin, Memphis Zhihong	361/686
*	E	US-5,854,617	12-1998	Lee et al.	345/102
*	F	US-6,462,941	10-2002	Hulick et al.	361/683
*	G	US-5,796,382	08-1998	Beeteson, John S.	345/102
*	H	US-5,696,529	12-1997	Evanicky et al.	345/659
*	I	US-6,417,833	07-2002	Takemoto, Takahiro	345/102
*	J	US-6,426,736	07-2002	Ishihara, Junji	345/102
*	K	US-6,483,698	11-2002	Loh, Philip Kwok Nan	361/686
*	L	US-6,711,005	03-2004	Martin, Cindy L.	361/683
*	M	US-2001/0043188	11-2001	NAKAMURA, ATSUNORI	345/102

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP5-95395	10-1991	Japan	KITAMURA, SHINICHI	—
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.